

<b>Notice of References Cited</b>		Application/Control No. 09/873,815	Applicant(s)/Patent Under Reexamination LAVORGNA ET AL.	
		Examiner Tan Dean D. Nguyen	Art Unit 3629	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,862,585	03-2005	Planalp et al.	707/1
*	B	US-6,581,039	06-2003	Marpe et al.	705/7
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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